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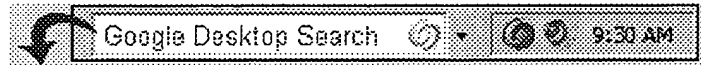www.epa.gov/otaq/url-fr/fr25au99.pdf - Similar pages

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